

AMENDMENTS TO THE SPECIFICATION

Please amend the paragraph beginning on page 25, line 13 as follows:

Next, FIG. [19] 2 shows a marking technique without gas deposition on a sample. An electron beam 901 is irradiated onto a sample 902 with scanning of the scanning width of X and Y 903. The electron beam 901 is directed continuously on the same area on the sample to cause charge up (charging phenomenon). Unordinal contrast due to charge up can be utilized for marking.